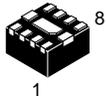


MECHANICAL CASE OUTLINE

PACKAGE DIMENSIONS

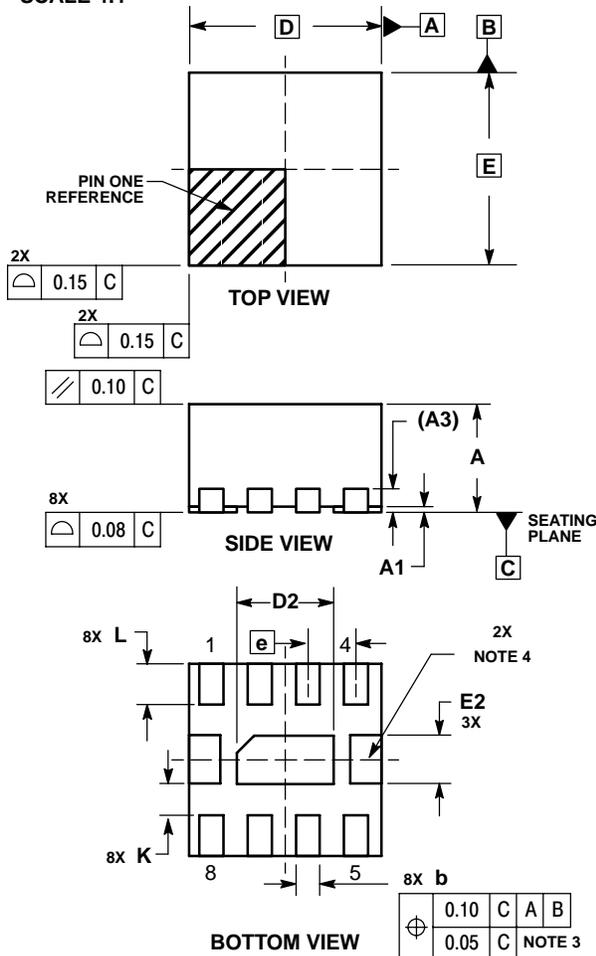
ON Semiconductor®



SCALE 4:1

DFN8
CASE 506AK-01
ISSUE C

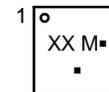
DATE 30 SEP 2005



- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. DIMENSION b APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.
 4. EXPOSED PADS CONNECTED TO DIE FLAG. USED AS TEST CONTACTS.

| DIM | MILLIMETERS | |
|-----|-------------|------|
| | MIN | MAX |
| A | 0.80 | 1.00 |
| A1 | 0.00 | 0.05 |
| A3 | 0.20 | REF |
| b | 0.15 | 0.25 |
| D | 1.60 | BSC |
| D2 | 0.70 | 0.90 |
| E | 1.60 | BSC |
| E2 | 0.30 | 0.50 |
| e | 0.40 | BSC |
| K | 0.20 | --- |
| L | 0.20 | 0.40 |

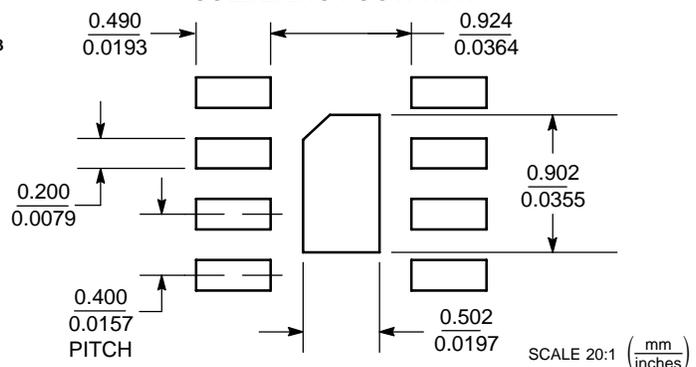
GENERIC MARKING DIAGRAM*



X = Specific Device Code
M = Date Code
▪ = Pb-Free Package
(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "▪", may or may not be present.

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

| | | |
|-------------------------|-----------------------------------|--|
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| STATUS: | ON SEMICONDUCTOR STANDARD | |
| NEW STANDARD: | | |
| DESCRIPTION: | DFN8 1.6*1.6 MM 0.4 MM LEAD PITCH | PAGE 1 OF 2 |

